Application of Machine Learning and Deep Learning in Pattern Recognition and Biometrics

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Message from the Guest Editors

The Special Issue "Application of Machine Learning and Deep Learning in Pattern Recognition and Biometrics" is OPEN!

This Special Issue focuses on state-of-the-art ML and DL techniques and their applications in PR. We seek contributions that include but are not limited to:

Novel applications of ML and DL in pattern recognition;

Biometrics applications based on ML and DL;

Multimodel biometrics based on ML and DL;

Novel datasets, challenges, and benchmarks for application and evaluation of pattern recognition and biometrics;

Review of new trends in pattern recognition and biometrics;

Applications of behavioral biometrics for human recognition.

Special Issue

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Message from the Editor-in-Chief

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